



3D v2 128Gb base 64GB eMMC5.1

Reliability Report

Part number H26M88002AMR

Structure 3D v2 128Gb MLC + Venus (eMMC5.1)

Solution Quality Assurance Group

General Information



♦ 3D v2 128GB ODP eMMC5.1 Venus

Product Device No.	Nand Flash	Controller
H26M88002AMR	3D v2 128Gb MLC *8	Venus (eMMC5.1)



3D v2 128Gb MLC Reliability Test Results



Reliability Item	Stress Condition	Sample Size	Criteria	Duration	Result	Remark
EFR	Reflow 260°C 1Cycle + Erase/Program/Read @ 125°C, 3.7V	2,500	400ppm	48Hrs	PASS (0ppm)	
HTOL	Read Stress @ 125°C, 3.6V	116	0	1008Hrs	PASS	
LTOL	Read Stress @ -10℃, 3.6V	76	0	1008Hrs	PASS	
Endurance	Erase/Program @ 85°C, 3.6V	231	0	3K	PASS	
HTDR	Pre-E/W 300/3K cycle @ 85℃, 3.6V Retention Bake @ 125℃	231	0	100/10Hrs	PASS	
LTDR	Pre-E/W 3K cycle @ 25℃, 3.6V Retention Bake @ 25℃	116	0	504Hrs	PASS	
Read Disturb	Pre-E/W 300/3K cycle @ 85°C, 3.6V Read Stress(SPRD) @ 25°C, 3.6V	116	0	3K + 500K	PASS	



3D v2 128GB eMMC5.1 Test Results



Test Item	Stress Condition	Sample Size	Criteria	Duration	Result	Remark
Read Disturb	PGM + 200LBA Read + 20LBA Read	32	0	2K+2M	Pass	
Reflow DR	PGM + 260°C Reflow 3Times + Read + Retention Bake @125°C+ Read	231	0	100Hrs	Pass	
UCHTDR	260°C Reflow 3Times + PGM + Retention Bake @125°C+ Read	231	0	100Hrs	Pass	
HTS	150℃ Storage	231	0	1008Hrs	Pass	
LTS	-65℃ Storage	231	0	1008Hrs	Pass	
ТНВ	85°C / 85%RH / 3.6V	231	0	1008Hrs	Pass	
T/C	-55 ℃ / 125 ℃	231	0	1000сус	Pass	
HAST	130°C / 85%RH / 3.6V	231	0	96Hrs	Pass	
Unbiased-HAST	110℃ / 85%RH	231	0	264Hrs	Pass	
ESD	HBM/MM/CDM(3/Mode)	3ea/Mode	2,000V/200V/500V	-	Pass	
Latch Up	Vsupply overvoltage/I Test	5ea/Mode	> Vmax*1.5 > Imax 100mA	-	Pass	
Package Crack	Preconditioning	22	0	-	Pass	
Warpage	Room, Reflow	22	0	-	Pass	

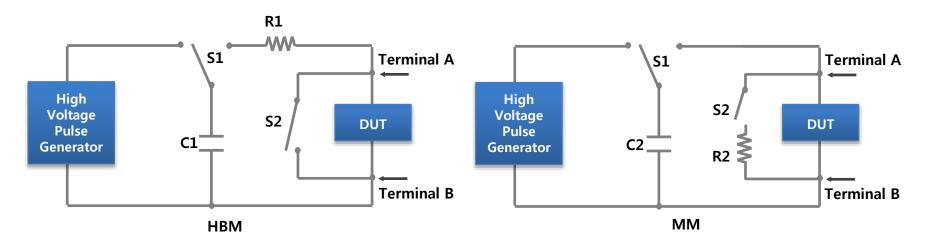
Note(*): Preconditioning Condition Flow for Surface Mount Packages

 $T/C(-55^{\circ}C/125^{\circ}C, 5Cycles) + Bake (125^{\circ}C, 24Hrs) + 85^{\circ}C/85\% (No Bias, 24Hrs) + Reflow (3Cycles, 260^{\circ}C)$





1. Test Circuit & Method



Model	Capacitor	Resister	Reference
НВМ	C1=100pF	R1=1500 OHM	JEDEC
MM	C2=200pF	R2=10K to 10M OHM	JEDEC

2. Test Result

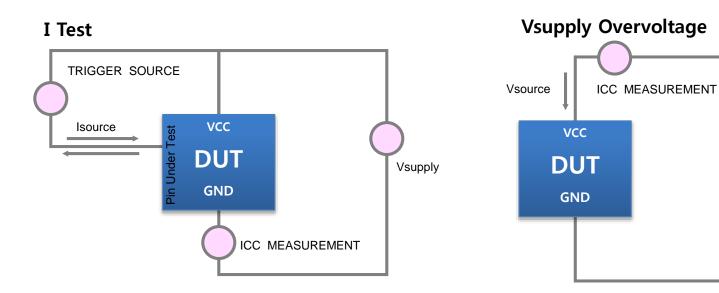
Method	Target	Result	Remark
HBM (Human Body Model)	≥ 2,000V	≥ 3,000V	
MM (Machine Model)	≥ 200V	≥ 200V	
CDM (Charged Device Model)	≥ 500V	≥ 500V	





Vsupply

3. Test Circuit & Method



4. Test Result

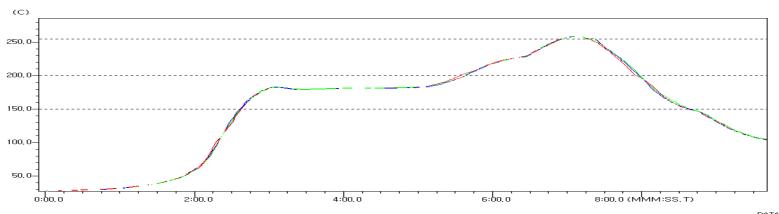
Method	Target	Result	Remark
I Test (Positive / Negative)	≥ ±100mA	≥ ±100mA	JEDEC
Vsupply Overvoltage	≥ (1.5xVdd)	≥ 5.4V	



Reflow Profile for Qualification



Reflow profile



Options	Time Above	Time Above	Ma× and Min T	emperatures in C			
Options	217.0C	255.HC	Ma× Temp	Ma× Time	Min Temp	Min Time	
	1:50.0	0:24.0	259.0	7:03.0	27.0	- 0:04.0	
2	1:52.0	0:22.0	259.0	7:03.0	27.0	- 0:04.0	
3	1:51.0	0:28.0	259.0	7:06.0	27.0	- 0:04.0	

Profile Feature	J-STD020C	SK Hynix (Actual Value)
Solder (SnAgCu) Melting Point	217℃	217°C
Average ramp-up rate	3.0 °C/ sec max.	2.0 °C / sec
Preheat	150 ~ 200 °C : 60 ~ 180 sec	150 ~ 200 °C : 150 sec
Time maintained above	217 °C : 60 ~ 150 sec	217 °C : 100 sec
Peak Temperature	255 ~ 260 °C : 20 ~ 40 sec	255 ~ 260 ℃ : 24 sec
Ramp-down rate	6 ℃ / sec max	1.3 °C / sec
Time 25'C to peak temperature	8 minutes max	7 minutes





1. Pre-con. test result: Electrical Test

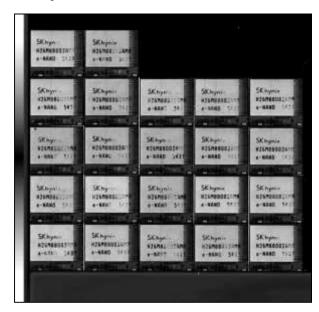
Sample Size	924 pcs	
Test result	PASS	
Remark	DC TEST (Open, Short, Pin leakage, ICC),	Functional Test : Magnum, 25°C

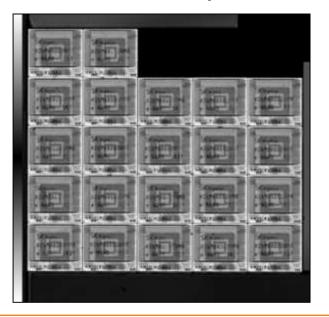
2. Pre-con. test result: Internal Visual inspection

Sample Size	22 pcs	
Test result	PASS	
Remark	There is no crack or delamination.	

Note) SK hynix Preconditioning Flow:

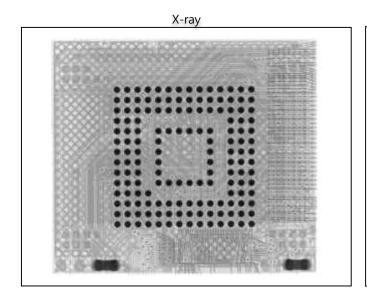
T/C(-55°C~125 °C) 5Cycle + Bake(125 °C) 24Hours + 85 °C /85%RH 24Hours + Reflow (260 °C) 3Cycle

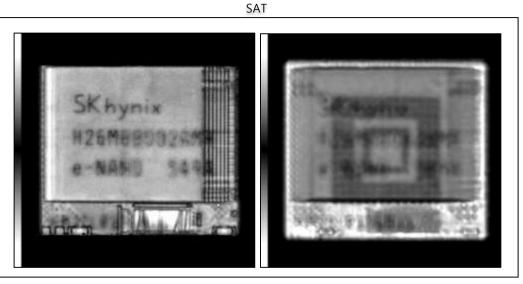




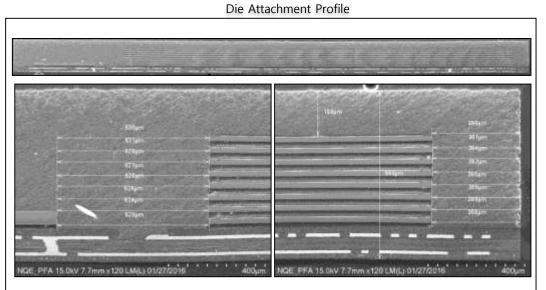


Package Construction





Wire Sweep Shape

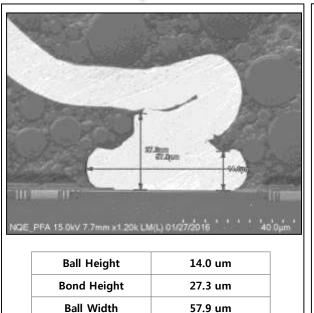




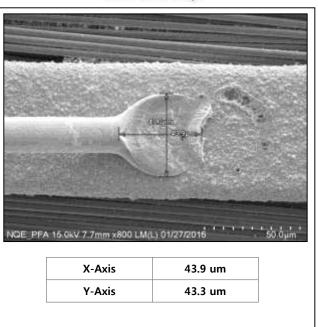
Package Construction



Ball Bonding Cross-Section



Stitch Bond Shape



Ball Bonding Shape

